

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Priority Application Serial No. 09/521,092
Priority Filing Date March 7, 2000
Inventor Scott E. Moore et al.
Assignee Micron Technology, Inc.
Priority Group Art Unit 3723
Priority Examiner W. Berry
Attorney's Docket No. MI22-2493
Customer No. 021567
Title: Turbidity Monitoring Methods, Apparatuses, and Sensors

INFORMATION DISCLOSURE STATEMENT
PURSUANT TO 37 C.F.R. §§ 1.56, 1.97 AND 1.98

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

The listed references were cited by, or submitted to, the Office in the parent, co-pending application of the above-identified application. The above-identified application is a divisional application of co-pending application Serial No. 09/521,092, filed March 7, 2000. Such prior disclosure is sufficient for the above-identified application as far as copies of the references are concerned.

37 C.F.R. § 1.98(d) and MPEP § 609(2).

EL979949712

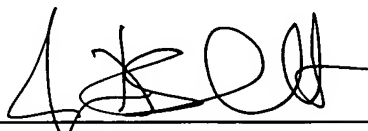
Citation of these references is respectfully requested.

Respectfully submitted,

Dated:

4/6/04

By:


James D. Shaurette
Reg. No. 39,833

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2493	PRIORITY SERIAL NO. 09/521.092	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Scott E. Moore et al.		
				PRIORITY FILING DATE March 7, 2000	PRIORITY GROUP 3723	
U.S. PATENT DOCUMENTS						
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,836,805	11/1998	Obeng		
	AB	6,066,030	5/2000	Uzoh		
	AC	6,077,147	6/2000	Yang et al.		
	AD	6,048,256	4/2000	Obeng et al.		
	AE	5,718,620	2/17/98	Tanaka et al.		
	AF	5,885,134	3/23/99	Shibata et al.		
	AG	6,099,386	8/8/00	Tsai et al.		
	AH	6,159,082	12/12/00	Sugiyama et al.		
	AI	6,165,048	12/26/00	Russ et al.		
	AJ	6,183,352	2/6/01	Kurisawa		
	AK	5,653,624	8/5/1997	Ishikawa et al.		
	AL	5,923,433	7/13/1999	Giuffre et al.		
	AM	6,136,043	10/24/2000	Robinson et al.		
	AN	6,482,325 B1	11/19/2002	Corlett et al.		
	AO	6,379,538 B1	4/30/2002	Corlett et al.		
	AP	5,755,614	5/26/1998	Adams et al.		
	AQ	5,664,990	9/9/1997	Adams et al.		
FOREIGN PATENT DOCUMENTS						
	Document Number	Date	Country	Class	Subclass	Translation
						Yes No
	AR					
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)						
	AS					
EXAMINER			DATE CONSIDERED			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>						

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2493		PRIORITY SERIAL NO. 09/521,092	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Scott E. Moore et al.			
				PRIORITY FILING DATE March 7, 2000		PRIORITY GROUP 3723	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AC						
	AC						
	AC						
	AE						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AH						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AI		"The Science and Engineering of Micronelectronic Fabrication"; Campbell, Stephen A.; Oxford University Press; 1996; pp. 253-257.				
	AI		http://www.intratechnology.com/html/sensors.htm, Intra Technology, <i>Sensore</i> , 03/25/99, 2 pages				
	AJ		http://www.ftsync.com/complete/analite/analite.htm, FTS, <i>Analite-SDI Turbidity Sensor</i> , 03/25/99, 1 page				
	AK		http://www.customsensors.com/optimax.htm, Custom Sensors & Technology, <i>OptiMax 6000 Series Process Photometric Analyzers</i> , 03/25/99, 2 pages				
	AL		http://www.reflectronics.com/reflectronics_inc_contents.htm, Reflectronics, Inc., <i>Fiber Optic Backscatter Sensor</i> , 03/25/99, 1 page				
	AM		http://www.honeywell.com/sensing/prodinfo/turbidity/technical/turbidity.st, Gary O'Brien, Honeywell, <i>Turbidity Sensor for Electromechanical Dishwasher Control</i> , 1998-1999, 11 pages				
	AT		http://www.impomag.com/O_automa/10970064.htm, ABB Instrumentation, The Stockroom, <i>Photodiode Sensor</i> , 1999, 1 page				
EXAMINER				DATE CONSIDERED			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							